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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 2 of 2

Com	plete if Known
Application Number	10/079,512
Filing Date	February 22, 2002
First Named Inventor	Shunpei YAMAZAKI
Art Unit	2826
Examiner Name	Remmon R. Forde
Attorney Docket Number	740756-2441

Examiner Initials	Cite No. ¹	Foreign Patent Document	FOREIGN PATENT DO Publication Date MM-DD-YYYY	Name of Patentee or	Pages, Cohumns, Lines, Where Relevant Passages or Relevant Figures Appear		
		Country Code ³ Number ⁴ Kind Code ³ (if known)		Application of Cited Document		τ '	
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		JP 10-294280	11-04-1998	Yamazaki et al.		Abstract	
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		OTHER PRIO	R ART – NON PATENT	LITERATURE DOCUMENTS			
Examiner nitials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.					
1.7.				GNED GATE-OVERLAI ERFORMANCE", IEDM			
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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	U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or	Pages, Columns, Lines, Where	
		Number - Kind Code ² (if known)		Applicant of Cited Document	Relevant Passages or Relevant Figures Appear	
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Examiner Initials	Cite No.	Foreign Patent Document Kind Code Country Code Number (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Cohimns, Lines, Whore Relevant Passages or Relevant Figures Appear	τ•
1-7.	+	JP-06-148685	05/27/1994	NAKAZONO et al.		Full
1.7.		JP-08-264784	10/11/1996	KUROKAWA		Partial
	!	OTHER PRIOR A	ART - NON PATENT L	ITERATURE DOCUMENTS		
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.)., date, page(s), volume-issue number(s), publisher, city and/or country where published.				
A. Z.	U.S. Patent Application Serial No. 09/433,705; Filed: November 4, 1999; Shunpei Yamazaki; "Method of Fabricating a Semiconductor Device" (Specification;. Claims, Abstract, Drawings, Official Filing Receipt and Official Action dated 3/12/04 with Partia English Translation of Japanese Patent No. 8-264784)); Status: Pending					al
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